

SI2307CDS

PRODUCT SUMMARY			
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, b}	Q _g (Typ.)
- 30	0.088 at V _{GS} = - 10 V	- 2.7	4.1 nC
	0.138 at V _{GS} = - 4.5 V	- 2.2	

FEATURES

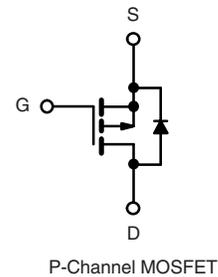
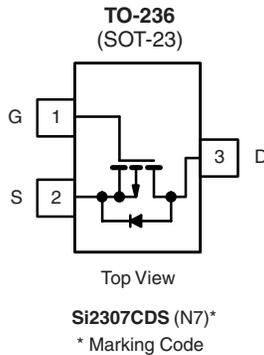
- Halogen-free Option Available
- TrenchFET® Power MOSFET



RoHS
COMPLIANT

APPLICATIONS

- Load Switch for Portable Devices



Ordering Information: Si2307CDS-T1-E3 (Lead (Pb)-free)
Si2307CDS-T1-GE3 (Lead (Pb)-free and Halogen-free)

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted			
Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 30	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current (T _J = 150 °C) ^{a, b}	I _D	T _C = 25 °C	- 3.5
		T _C = 70 °C	- 2.8
		T _A = 25 °C	- 2.7 ^{a, b}
		T _A = 70 °C	- 2.2 ^{a, b}
Pulsed Drain Current (10 μs Pulse Width)	I _{DM}	- 12	A
Continuous Source-Drain Diode Current ^{a, b}	I _S	T _C = 25 °C	
		T _A = 25 °C	- 0.91 ^{a, b}
Maximum Power Dissipation ^{a, b}	P _D	T _C = 25 °C	1.8
		T _C = 70 °C	1.14
		T _A = 25 °C	1.1 ^{a, b}
		T _A = 70 °C	0.7 ^{a, b}
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temperature) ^c		260	

THERMAL RESISTANCE RATINGS					
Parameter	Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	R _{thJA}	90	115	°C/W	
Maximum Junction-to-Foot (Drain)	R _{thJF}	55	70		

Notes:

a. Surface Mounted on 1" x 1" FR4 board.

b. t = 5 s.

c. Maximum under Steady State conditions is 166 °C/W.



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SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}, I_D = -250\text{ }\mu\text{A}$	-30			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250\text{ }\mu\text{A}$		-32		mV/°C
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$		4.5			
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -250\text{ }\mu\text{A}$	-1		-3	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = \pm 20\text{ V}$			-100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -30\text{ V}, V_{GS} = 0\text{ V}$			-1	μA
		$V_{DS} = -30\text{ V}, V_{GS} = 0\text{ V}, T_J = 55\text{ }^\circ\text{C}$			-10	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \leq 5\text{ V}, V_{GS} = -10\text{ V}$	-6			A
Drain-Source On-State Resistance ^a	$R_{DS(on)}$	$V_{GS} = -10\text{ V}, I_D = -3.5\text{ A}$		0.073	0.088	Ω
		$V_{GS} = -4.5\text{ V}, I_D = -2.5\text{ A}$		0.110	0.138	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -10\text{ V}, I_D = -3.5\text{ A}$		7		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = -15\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$		340		pF
Output Capacitance	C_{oss}		67			
Reverse Transfer Capacitance	C_{rss}		51			
Total Gate Charge	Q_g	$V_{DS} = -15\text{ V}, V_{GS} = -4.5\text{ V}, I_D = -2.5\text{ A}$		4.1	6.2	nC
Gate-Source Charge	Q_{gs}		1.3			
Gate-Drain Charge	Q_{gd}		1.8			
Gate Resistance	R_g	$f = 1\text{ MHz}$		10		Ω
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -15\text{ V}, R_L = 15\text{ }\Omega$ $I_D \cong -1\text{ A}, V_{GEN} = -4.5\text{ V}, R_g = 1\text{ }\Omega$		40	60	ns
Rise Time	t_r		40	60		
Turn-Off Delay Time	$t_{d(off)}$		20	40		
Fall Time	t_f		17	30		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = -15\text{ V}, R_L = 15\text{ }\Omega$ $I_D \cong -1\text{ A}, V_{GEN} = -10\text{ V}, R_g = 1\text{ }\Omega$		5.5	10	
Rise Time	t_r		13	25		
Turn-Off Delay Time	$t_{d(off)}$		17	30		
Fall Time	t_f		7.7	15		
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^\circ\text{C}$			-1.5	A
Pulse Diode Forward Current	I_{SM}				-12	
Body Diode Voltage	V_{SD}	$I_S = -0.75\text{ A}, V_{GS} = 0\text{ V}$		-0.8	-1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -2.5\text{ A}, dI/dt = 100\text{ A}/\mu\text{s}, T_J = 25\text{ }^\circ\text{C}$		17	30	ns
Body Diode Reverse Recovery Charge	Q_{rr}		11	20	nC	
Reverse Recovery Fall Time	t_a		12		ns	
Reverse Recovery Rise Time	t_b		5			

Notes:

a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.

b. Guaranteed by design, not subject to production testing.